

Integrated RF Test Solution

Keysight Technologies and
Marvin Test Solutions

PXI-based, high performance ATE for component, SOC and SIP test

The ongoing challenge for today's semiconductor test engineers is to identify and create new test solutions that can achieve significantly lower Cost of Test and a smaller footprint while providing comparable features to proprietary ATE platforms. The PXI platform offers test engineers a flexible and cost-effective test solution for today's mixed-signal/RF devices.

Combining Marvin Test Solutions' TS-960e PXI platform with Keysight Technologies' RF instrumentation, customers can address a wide range of RF and mixed-signal devices for both wafer and packaged test.



The TS-960e's open architecture can accommodate the full range of Keysight's RF PXI products, Marvin Test Solutions' extensive line of digital test products, as well as thousands of available PXI and PXIe instruments.

System software includes MTS' ATEasy software suite which provides an integrated test executive and test development environment as well as the ICEasy Test Suite. Optionally, Keysight's X series and VSA software can be integrated with ATEasy, automating measurement and signal analysis for a wide range of RF applications.

The system can address a wide range of applications including: WLAN components and modules; Bluetooth components and modules; cellular products; power amplifiers; RF components; baseband devices; EW/RADAR and communications devices..

- 21 slot, manipulator-ready, high power PXIe platform with integrated receiver
- Supports a wide range of RF test applications, 9 KHz to 50 GHz; for wafer and packaged test
- RF instrumentation options include Keysight's vector signal generators, vector signal analyzers, and vector network analyzers
- Advanced digital subsystem, with PMU, and timing per pin with sub-nsec edge placement
- Support for baseband test applications using MTS and Keysight PXI/PXIe switching and instrumentation
- Full featured, open architecture software tools support device characterization and production test

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The test system is supplied with ATEasy and all instrument drivers, virtual instrument panels and a system self-test, as well as the ICEasy Test Suite which offers a comprehensive set of software tools for device test development and characterization. ATEasy supports a wide variety of Windows- based APIs including ATEasy, LabVIEW, CVI, Microsoft and Borland C/C++, Microsoft Visual Basic, and Borland Delphi.

Marvin Test Solutions' TS-960e PXI platform, when combined with Keysight Technologies' PXI RF instrumentation, offers a fully integrated test solution for RF and mixed-signal devices for both wafer and packaged test.

System Components

Keysight Technologies

M938x/M942x	PXI Vector Signal Generators
M9290A	PXIe Vector Signal Analyzer
M937x	PXIe Vector Network Analyzers

Marvin Test Solutions

TS-960e	PXI test platform
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To learn how this solution can address your specific needs please contact

Keysight's solutions partner,
Marvin Test Solutions

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